74AHC1GU04-Q100

Inverter

Rev. 1 — 21 November 2012

Product data sheet

1. General description

The 74AHC1GU04-Q100 is a high-speed Si-gate CMOS device. It provides an inverting single stage function.

The AHC device has CMOS input switching levels and supply voltage range 2 V to 5.5 V.

This product has been qualified to the Automotive Electronics Council (AEC) standard Q100 (Grade 1) and is suitable for use in automotive applications.

2. Features and benefits

- Automotive product qualification in accordance with AEC-Q100 (Grade 1)
 - ◆ Specified from -40 °C to +85 °C and from -40 °C to +125 °C
- Symmetrical output impedance
- High noise immunity
- Low power dissipation
- Balanced propagation delays
- ESD protection:
 - ◆ MIL-STD-883, method 3015 exceeds 2000 V
 - ♦ HBM JESD22-A114F exceeds 2000 V
 - ♦ MM JESD22-A115-A exceeds 200 V (C = 200 pF, R = 0 Ω)

3. Ordering information

Table 1. Ordering information

Type number	Package											
	Temperature range	Name	Description	Version								
74AHC1GU04GW-Q100	–40 °C to +125 °C	TSSOP5	plastic thin shrink small outline package; 5 leads; body width 1.25 mm	SOT353-1								
74AHC1GU04GV-Q100	−40 °C to +125 °C	SC-74A	plastic surface-mounted package; 5 leads	SOT753								

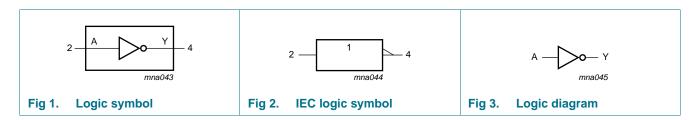
4. Marking

Table 2. Marking codes

Type number	Marking
74AHC1GU04GW-Q100	AD
74AHC1GU04GV-Q100	AU4

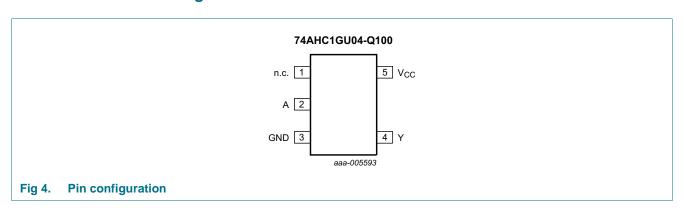


5. Functional diagram



6. Pinning information

6.1 Pinning



6.2 Pin description

Table 3. Pin description

Symbol	Pin	Description
n.c.	1	not connected
A	2	data input
GND	3	ground (0 V)
Υ	4	data output
V _{CC}	5	supply voltage

7. Functional description

Table 4. Function table

 $H = HIGH \ voltage \ level; \ L = LOW \ voltage \ level$

Input	Output
A	Υ
L	Н
Н	L

74AHC1GU04_Q100

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CC}	supply voltage		-0.5	+7.0	V
I _{IK}	input clamping current	$V_{I} < -0.5 \text{ V}$	-20	-	mA
VI	input voltage		<u>[1]</u> –0.5	+7.0	V
l _{OK}	output clamping current	V_{O} < -0.5 V or V_{O} > V_{CC} + 0.5 V	-	±20	mA
Io	output current	$-0.5 \text{ V} < \text{V}_{\text{O}} < \text{V}_{\text{CC}} + 0.5 \text{ V}$	-	±25	mA
I _{CC}	supply current		-	75	mA
I_{GND}	ground current		-75	-	mA
T _{stg}	storage temperature		-65	+150	°C
P _{tot}	total power dissipation	$T_{amb} = -40 ^{\circ}\text{C}$ to +125 $^{\circ}\text{C}$	[2] -	250	mW

^[1] The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

9. Recommended operating conditions

Table 6. Recommended operating conditions

Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{CC}	supply voltage		2.0	5.0	5.5	V
V_{I}	input voltage		0	-	5.5	V
Vo	output voltage		0	-	V_{CC}	V
T _{amb}	ambient temperature		-40	+25	+125	°C
Δt/ΔV	input transition rise and fall rate	V_{CC} = 3.3 V \pm 0.3 V	-	-	100	ns/V
		V_{CC} = 5.0 V \pm 0.5 V	-	-	20	ns/V

10. Static characteristics

Table 7. Static characteristics

Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		25 °C		-40 °C	to +85 °C	–40 °C t	Unit	
			Min	Тур	Max	Min	Max	Min	Max	
V_{IH}	HIGH-level input voltage	V _{CC} = 2.0 V	1.7	-	-	1.7	-	1.7	-	V
		V _{CC} = 3.0 V	2.4	-	-	2.4	-	2.4	-	V
		V _{CC} = 5.5 V	4.4	-	-	4.4	-	4.4	-	V
V_{IL}	LOW-level	$V_{CC} = 2.0 \text{ V}$	-	-	0.3	-	0.3	-	0.3	V
	input voltage	$V_{CC} = 3.0 \text{ V}$	-	-	0.6	-	0.6	-	0.6	V
		V _{CC} = 5.5 V	-	-	1.1	-	1.1	-	1.1	V

^[2] For both TSSOP5 and SC-74A packages: above 87.5 °C the value of Ptot derates linearly with 4.0 mW/K.

Table 7. Static characteristics ...continued Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions		25 °C		-40 °C	to +85 °C	-40 °C	to +125 °C	Unit
			Min	Тур	Max	Min	Max	Min	Max	
V_{OH}	HIGH-level	$V_I = V_{IH}$ or V_{IL}								
	output voltage	$I_O = -50 \mu A; V_{CC} = 2.0 V$	1.9	2.0	-	1.9	-	1.9	-	V
		$I_O = -50 \mu A; V_{CC} = 3.0 V$	2.9	3.0	-	2.9	-	2.9	-	V
		$I_O = -50 \mu A; V_{CC} = 4.5 V$	4.4	4.5	-	4.4	-	4.4	-	V
		$I_{O} = -4.0 \text{ mA}; V_{CC} = 3.0 \text{ V}$	2.58	-	-	2.48	-	2.40	-	V
		$I_{O} = -8.0 \text{ mA}; V_{CC} = 4.5 \text{ V}$	3.94	-	-	3.8	-	3.70	-	V
V_{OL}	LOW-level output voltage	$V_I = V_{IH}$ or V_{IL}								
		$I_O = 50 \mu A; V_{CC} = 2.0 V$	-	0	0.1	-	0.1	-	0.1	V
		$I_O = 50 \mu A; V_{CC} = 3.0 V$	-	0	0.1	-	0.1	-	0.1	V
		$I_O = 50 \mu A; V_{CC} = 4.5 V$	-	0	0.1	-	0.1	-	0.1	V
		$I_O = 4.0 \text{ mA}; V_{CC} = 3.0 \text{ V}$	-	-	0.36	-	0.44	-	0.55	V
		$I_O = 8.0 \text{ mA}; V_{CC} = 4.5 \text{ V}$	-	-	0.36	-	0.44	-	0.55	V
I _I	input leakage current	$V_I = 5.5 \text{ V or GND};$ $V_{CC} = 0 \text{ V to 5.5 V}$	-	-	0.1	-	1.0	-	2.0	μΑ
I _{CC}	supply current	$V_I = V_{CC}$ or GND; $I_O = 0$ A; $V_{CC} = 5.5 \text{ V}$	-	-	1.0	-	10	-	40	μА
C _I	input capacitance		-	1.5	10	-	10	-	10	pF

11. Dynamic characteristics

Table 8. Dynamic characteristics

 $GND = 0 \ V; \ t_f = t_f = \le 3.0 \ ns.$ For test circuit see <u>Figure 6</u>.

Symbol	Parameter	Conditions			25 °C		-40 °C	to +85 °C	-40 °C	to +125 °C	Unit
				Min	Тур	Max	Min	Max	Min	Max	
t _{pd}	propagation	A to Y; see Figure 5	<u>[1]</u>				'			'	
	delay	$V_{CC} = 3.0 \text{ V to } 3.6 \text{ V}$	[2]								
		$C_{L} = 15 pF$		-	3.4	7.1	1.0	8.5	1.0	10.0	ns
		$C_{L} = 50 \text{ pF}$		-	4.9	10.6	1.0	12.0	1.0	13.5	ns
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	[3]								
		$C_{L} = 15 pF$		-	2.6	5.5	1.0	6.0	1.0	7.0	ns
		$C_{L} = 50 \text{ pF}$		-	3.6	7.0	1.0	8.0	1.0	9.0	ns
C _{PD} power dissipation capacitance		per buffer; $V_I = GND$ to V_{CC}		-	14	-	-	-	-	-	pF

^[1] t_{pd} is the same as t_{PLH} and t_{PHL} .

 $P_D = C_{PD} \times V_{CC}^2 \times f_i + \sum (C_L \times V_{CC}^2 \times f_o)$ where:

 f_i = input frequency in MHz;

74AHC1GU04_Q100

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^[2] Typical values are measured at $V_{CC} = 3.3 \text{ V}$.

^[3] Typical values are measured at $V_{CC} = 5.0 \text{ V}$.

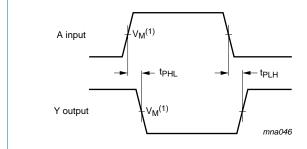
^[4] $\,$ C $_{PD}$ is used to determine the dynamic power dissipation P $_{D}$ (µW).

 f_o = output frequency in MHz;

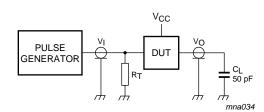
C_L = output load capacitance in pF;

 V_{CC} = supply voltage in Volts.

12. Waveforms



 $V_M = 0.5 \times V_{CC}$; $V_I = GND$ to V_{CC} .



Test data is given in Table 8.

Definitions for test circuit:

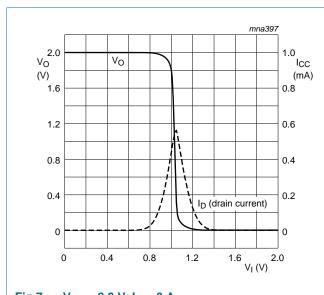
 C_L = Load capacitance including jig and probe capacitance.

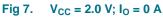
 $R_T = \mbox{Termination} \ \mbox{resistance} \ \mbox{should} \ \mbox{be} \ \mbox{equal} \ \mbox{to} \ \mbox{output} \ \mbox{impedance} \ \mbox{Z_o} \ \mbox{of} \ \mbox{the} \ \mbox{pulse} \ \mbox{generator}.$

Fig 5. The input (A) to output (Y) propagation delay times

Fig 6. Load circuitry for switching times

13. Typical transfer characteristics





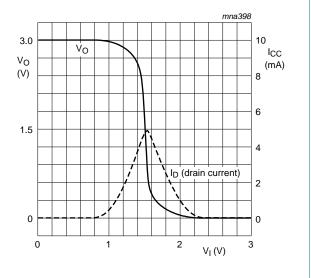
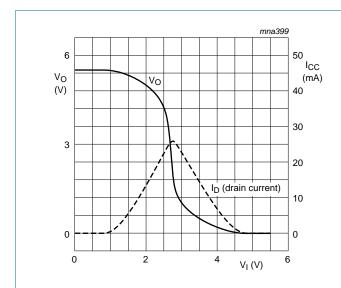


Fig 8. $V_{CC} = 3.0 \text{ V}; I_O = 0 \text{ A}$



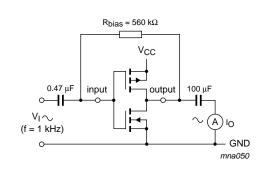


Fig 9. $V_{CC} = 5.5 \text{ V}; I_O = 0 \text{ A}$

Fig 10. Test set-up for measuring forward transconductance $g_{fs} = \Delta I_O/\Delta V_I$ at V_O is constant

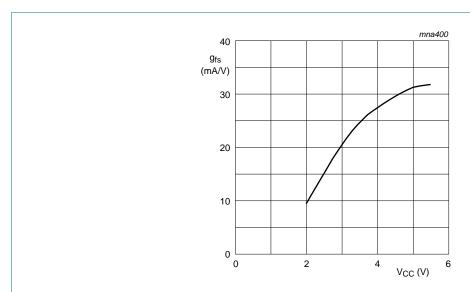


Fig 11. Typical forward transconductance g_{fs} as a function of the supply voltage at T_{amb} = 25 °C

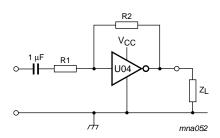
14. Application information

Some applications are:

- Linear amplifier (see Figure 12)
- In crystal oscillator design (see Figure 13)

Remark: All values given are typical unless otherwise specified.

74AHC1GU04_Q100



Maximum $V_{o(p-p)} = V_{CC} - 1.5 \text{ V}$ centered at $0.5 \times V_{CC}$.

$$G_v = -\frac{G_{ol}}{I + \frac{RI}{R2}(I + G_{ol})}$$

Gol = open loop gain

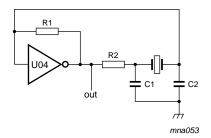
G_v = voltage gain

 $R1 \geq 3 \; k\Omega, \; R2 \leq 1 \; M\Omega$

 $Z_L > 10 \text{ k}\Omega$; $G_{ol} = 20 \text{ (typical)}$

Typical unity gain bandwidth product is 5 MHz.





C1 = 47 pF (typical)

C2 = 22 pF (typical)

R1 = 1 M Ω to 10 M Ω (typical)

R2 optimum value depends on the frequency and required stability against changes in V_{CC} or average minimum I_{CC} (I_{CC} is typically 2 mA at V_{CC} = 3 V and f = 1 MHz).

Fig 13. Crystal oscillator configuration

Table 9. External components for resonator (f < 1 MHz)

All values given are typical and must be used as an initial set-up.

Frequency	R1	R2	C1	C2	
10 kHz to 15.9 kHz	22 M Ω	220 kΩ	56 pF	20 pF	
16 kHz to 24.9 kHz	22 MΩ	220 kΩ	56 pF	10 pF	
25 kHz to 54.9 kHz	22 MΩ	100 kΩ	56 pF	10 pF	
55 kHz to 129.9 kHz	22 MΩ	100 kΩ	47 pF	5 pF	
130 kHz to 199.9 kHz	22 MΩ	47 kΩ	47 pF	5 pF	
200 kHz to 349.9 kHz	22 MΩ	47 kΩ	47 pF	5 pF	
350 kHz to 600 kHz	22 MΩ	47 kΩ	47 pF	5 pF	

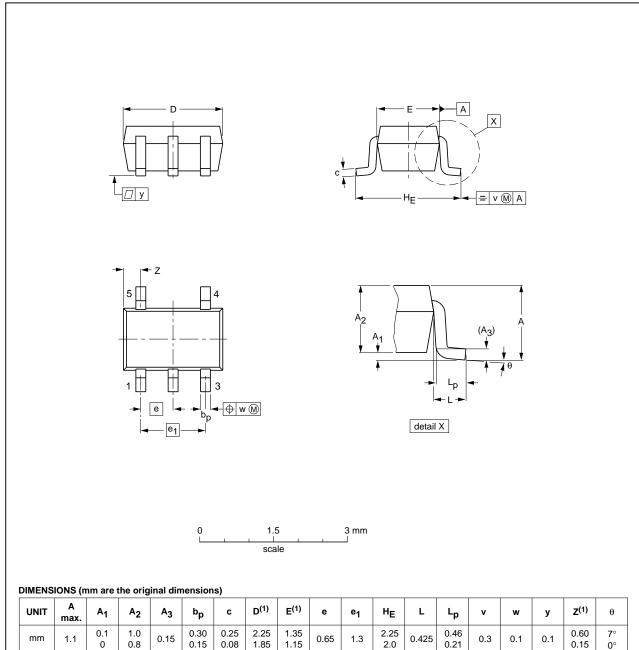
Table 10. Optimum value for R2

Frequency	R2	Optimum for
3 kHz	$2.0~\mathrm{k}\Omega$	minimum required I _{CC}
	8.0 kΩ	minimum influence due to change in V _{CC}
6 kHz	1.0 kΩ	minimum required I _{CC}
	4.7 kΩ	minimum influence by V _{CC}
10 kHz	$0.5~\mathrm{k}\Omega$	minimum required I _{CC}
	2.0 kΩ	minimum influence by V _{CC}
14 kHz	$0.5~\mathrm{k}\Omega$	minimum required I _{CC}
	1.0 kΩ	minimum influence by V _{CC}
>14 kHz	-	replace R2 by C3 with a typical value of 35 pF

15. Package outline

TSSOP5: plastic thin shrink small outline package; 5 leads; body width 1.25 mm

SOT353-1



UNIT	A max.	A ₁	A ₂	A ₃	bp	С	D ⁽¹⁾	E ⁽¹⁾	е	e ₁	HE	L	Lp	v	w	у	Z ⁽¹⁾	θ
mm	1.1	0.1 0	1.0 0.8	0.15	0.30 0.15	0.25 0.08	2.25 1.85	1.35 1.15	0.65	1.3	2.25 2.0	0.425	0.46 0.21	0.3	0.1	0.1	0.60 0.15	7° 0°

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

	REFERENCES			EUROPEAN	ISSUE DATE
IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE
	MO-203	SC-88A			00-09-01 03-02-19
: 	I IEC	I IEC JEDEC	I IEC JEDEC JEITA	I IEC JEDEC JEITA	I IEC JEDEC JEITA PROJECTION

Fig 14. Package outline SOT353-1 (TSSOP5)

74AHC1GU04_Q100

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Plastic surface-mounted package; 5 leads

SOT753

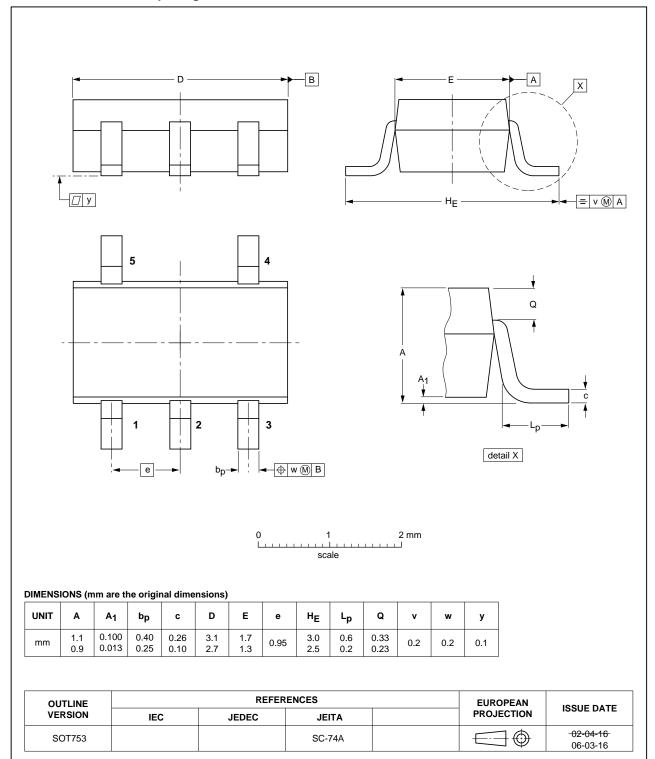


Fig 15. Package outline SOT753 (SC-74A)

16. Abbreviations

Table 11. Abbreviations

Acronym	Description
CMOS	Complementary Metal Oxide Semiconductor
CDM	Charged Device Model
DUT	Device Under Test
ESD	ElectroStatic Discharge
НВМ	Human Body Model
MIL	Military
MM	Machine Model

17. Revision history

Table 12. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
74AHC1GU04_Q100 v.1	20121121	Product data sheet	-	-

18. Legal information

18.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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20. Contents

1	General description
2	Features and benefits 1
3	Ordering information
4	Marking 1
5	Functional diagram 2
6	Pinning information
6.1	Pinning
6.2	Pin description 2
7	Functional description 2
8	Limiting values
9	Recommended operating conditions 3
10	Static characteristics 3
11	Dynamic characteristics 4
12	Waveforms
13	Typical transfer characteristics 5
14	Application information 6
15	Package outline 8
16	Abbreviations
17	Revision history
18	Legal information
18.1	Data sheet status
18.2	Definitions
18.3	Disclaimers
18.4	Trademarks
19	Contact information 12
20	Contents

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